

Search Notes

Application/Control No.

10/648,340

Examiner

W. Patty Chen

Applicant(s)/Patent under
Reexamination

OGISHIMA ET AL.

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
349/129 combined with 349/111 search of all databases in EAST	6/5/2007	WPC
349/96 combined with 349/129 search of all databases in EAST	6/5/2007	WPC
Citations search of relevant references	6/5/2007	WPC
349/129 combined with key words search of all databases in EAST	6/5/2007	WPC